

## Reliability Monitoring Results

Quarters: Q1/2023 to Q4/2023

Based on structural similarity

| Supplier   |   | User Part Number            |           |            |           |  |
|--|---|-----------------------------|-----------|------------|-----------|--|
| Nexperia B.V.  |   | 74LVCH8T245PW               |           |            |           |  |
| <b>Part Description:</b> 8-bit dual-supply voltage translating transceiver with bus hold (3-state) |   |                             |           |            |           |  |
| Function Family: LVC<br>Process family: Sub micron<br>Package family: TSSOP                        |   |                             |           |            |           |  |
| JESD47 Test  | Test Conditions                                       | Duration                    | # Lots    | # Quantity | # Rejects |  |
| # 1<br><b>TEST</b><br>Pre- and Post-Stress<br>Electrical Test                                      | Tamb = 25 °C  | N/A                         | see below | all parts  | see below |  |
| # 2<br><b>PC</b><br>Preconditioning  | JESD22-A113<br>MSL 1                                  | N/A                         | 1107      | 88843      | 0         |  |
| # 5a<br><b>HTOL EFR</b><br>High Temperature<br>Operating Life Extrinsic                            | JESD22-A108<br>Tj = 150°C<br>VCCMAX ≤ V ≤ 1.2*VCCMAX  | 48 hours<br>or<br>168 hours | 136       | 33576      | 0         |  |
| # 5b<br><b>HTOL IFR</b><br>High Temperature<br>Operating Life Intrinsic                            | JESD22-A108<br>Tj = 150°C<br>VCCMAX ≤ V ≤ 1.2*VCCMAX  | ≥500 hours                  | 93        | 7373       | 0         |  |
| # 7<br><b>TC</b><br>Temperature Cycling  | JESD22-A104<br>-65 °C to 150°C                        | ≥500 cycles                 | 585       | 45629      | 0         |  |
| # 9<br><b>uHAST / HAST</b><br>unbiased or biased High<br>Accelerated Stress Test                   | JESD22-A101<br>Tamb = 130 °C,<br>RH = 85%, V = VCCMAX | 96 hours                    | 559       | 43214      | 0         |  |

### Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above)

Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic (HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Product Family | Package Family | Quantity | Rejects | Extrinsic Failure Rate (PPM) | Intrinsic Failure Rate (FIT) | MTTF (hrs) |
|----------------|----------------|----------|---------|------------------------------|------------------------------|------------|
| LVC            | TSSOP          | 7373     | 0       | 28                           | 0.5                          | 2.16 E+09  |